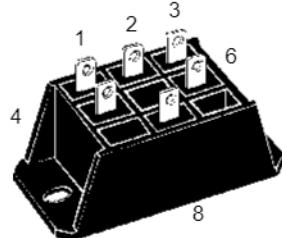
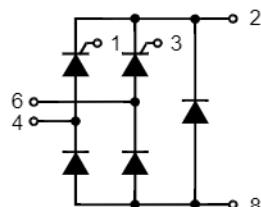


Half Controlled Single Phase Rectifier Bridge with Freewheeling Diode

$I_{dAVM} = 21 \text{ A}$
 $V_{RRM} = 800-1600 \text{ V}$

V_{RSM} V	V_{RRM} V	Type
V_{DSM}	V_{DRM}	
900	800	VHF 15-08i05
1300	1200	VHF 15-12i05
1500	1400	VHF 15-14i05
1700	1600	VHF 15-16i05



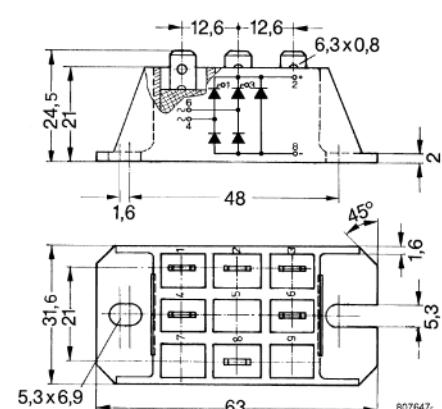
Symbol	Test Conditions	Maximum Ratings			Features
I_{dAV}	$T_K = 85^\circ\text{C}$, module	15	A		
I_{dAVM} ①	module	21	A		
I_{FRMS}, I_{TRMS}	per leg	15	A		
I_{FSM}, I_{TSM}	$T_{VJ} = 45^\circ\text{C}$; $V_R = 0 \text{ V}$	190	A		
	$t = 10 \text{ ms}$ (50 Hz), sine $t = 8.3 \text{ ms}$ (60 Hz), sine	210	A		
	$T_{VJ} = T_{VJM}$ $V_R = 0 \text{ V}$	170	A		
	$t = 10 \text{ ms}$ (50 Hz), sine $t = 8.3 \text{ ms}$ (60 Hz), sine	190	A		
I^2t	$T_{VJ} = 45^\circ\text{C}$ $V_R = 0 \text{ V}$	160	A^2s		
		180	A^2s		
	$T_{VJ} = T_{VJM}$ $V_R = 0 \text{ V}$	140	A^2s		
		145	A^2s		
$(di/dt)_{cr}$	$T_{VJ} = 125^\circ\text{C}$ $f = 50 \text{ Hz}, t_p = 200 \mu\text{s}$ $V_D = 2/3 V_{DRM}$ $I_G = 0.3 \text{ A}$, $di_G/dt = 0.3 \text{ A}/\mu\text{s}$	repetitive, $I_T = 50 \text{ A}$	150	$\text{A}/\mu\text{s}$	
		non repetitive, $I_T = 1/2 \cdot I_{dAV}$	500	$\text{A}/\mu\text{s}$	
$(dv/dt)_{cr}$	$T_{VJ} = T_{VJM}; V_{DR} = 2/3 V_{DRM}$ $R_{GK} = \infty$; method 1 (linear voltage rise)		1000	$\text{V}/\mu\text{s}$	
V_{RGM}			10	V	
P_{GM}	$T_{VJ} = T_{VJM}$ $I_T = I_{TAVM}$	$t_p = 30 \mu\text{s}$ $t_p = 500 \mu\text{s}$ $t_p = 10 \text{ ms}$	≤ 10 ≤ 5 ≤ 1 0.5	W	
P_{GAVM}			-40...+125	$^\circ\text{C}$	
T_{VJ}			125	$^\circ\text{C}$	
T_{VJM}			-40...+125	$^\circ\text{C}$	
T_{stg}					
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1 \text{ mA}$	$t = 1 \text{ min}$ $t = 1 \text{ s}$	3000 3600	$\text{V}\sim$	
M_d	Mounting torque (M5) (10-32 UNF)		2-2.5 18-22	Nm lb.in.	
Weight			50	g	

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.

① for resistive load

IXYS reserves the right to change limits, test conditions and dimensions.

Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
I_R, I_D	$V_R = V_{RRM}; V_D = V_{DRM}$ $T_{VJ} = T_{VJM}$ $T_{VJ} = 25^\circ C$	≤ 5 mA	≤ 0.3 mA	
V_T, V_F	$I_T, I_F = 45 A; T_{VJ} = 25^\circ C$	≤ 2.8 V		
V_{TO}	For power-loss calculations only ($T_{VJ} = 125^\circ C$)	1.0 V		
r_T		40 mΩ		
V_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$	≤ 1.0 V	≤ 1.2 V	
I_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤ 65 mA	≤ 80 mA	≤ 50 mA
V_{GD}	$T_{VJ} = T_{VJM};$ $T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤ 0.2 V	
I_{GD}	$T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤ 5 mA	
I_L	$I_G = 0.3 A; t_g = 30 \mu s;$ $di_g/dt = 0.3 A/\mu s;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤ 150 mA	≤ 200 mA	≤ 100 mA
I_H	$T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$	≤ 100 mA		
t_{gd}	$T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$ $I_G = 0.3 A; di_g/dt = 0.3 A/\mu s$	≤ 2 μs		
t_q	$T_{VJ} = 125^\circ C, I_T = 15 A, t_p = 300 \mu s, V_R = 100 V$	typ. 150 μs		
Q_r	$di/dt = -10 A/\mu s, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$	75 μC		
R_{thJC}	per thyristor (diode); DC current	2.4 K/W		
	per module	0.6 K/W		
R_{thJK}	per thyristor (diode); DC current	3.0 K/W		
	per module	0.75 K/W		
d_s	Creepage distance on surface	12.6 mm		
d_a	Creepage distance in air	6.3 mm		
a	Max. allowable acceleration	50 m/s²		

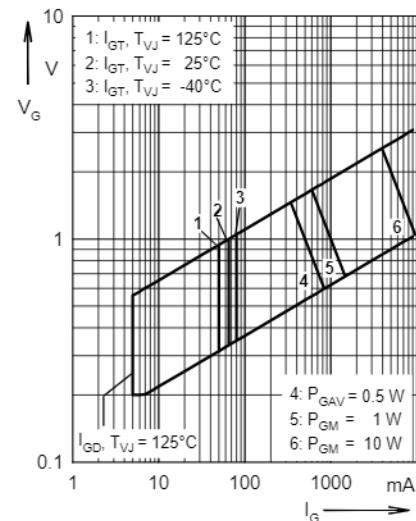
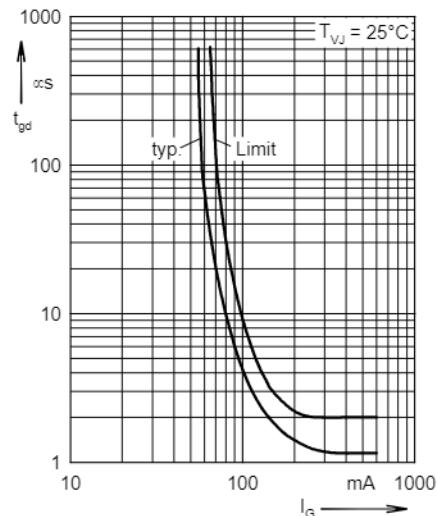


Fig. 1 Gate trigger range

Fig. 2 Gate controlled delay time t_{gd}

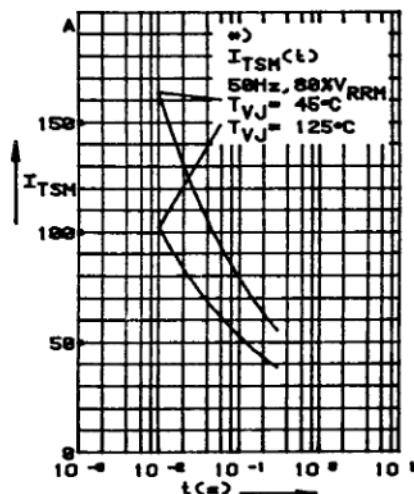


Fig. 3 Surge overload current per chip
 I_{TSM} : Crest value, t : duration

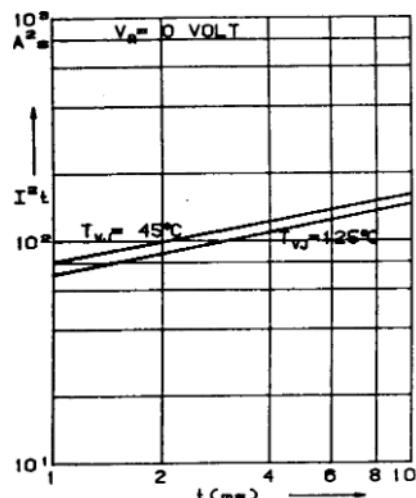


Fig. 4 I^2t versus time (1-10 ms)
 per chip

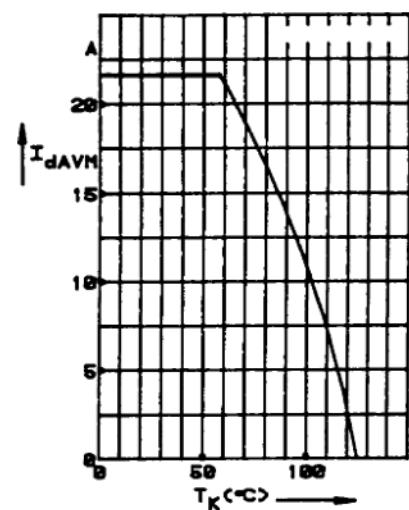


Fig. 5 Max. forward current at
 heatsink temperature

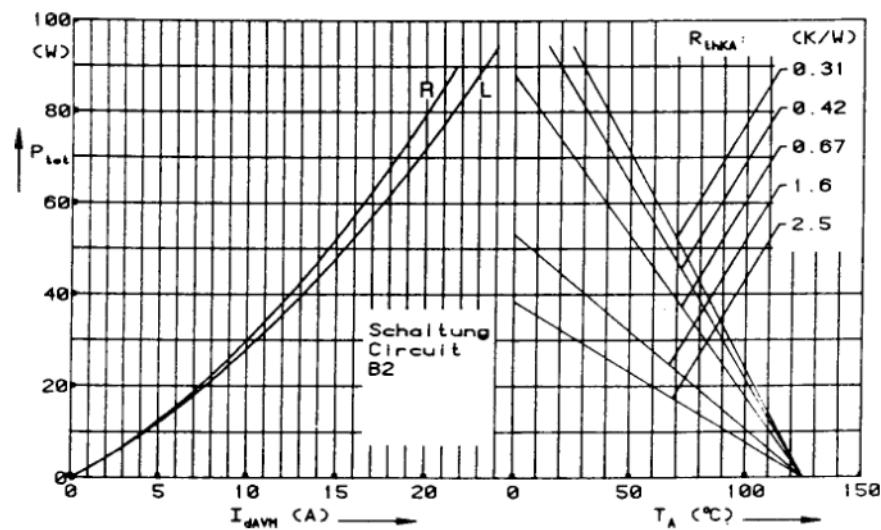


Fig. 6 Power dissipation versus direct output current and ambient temperature

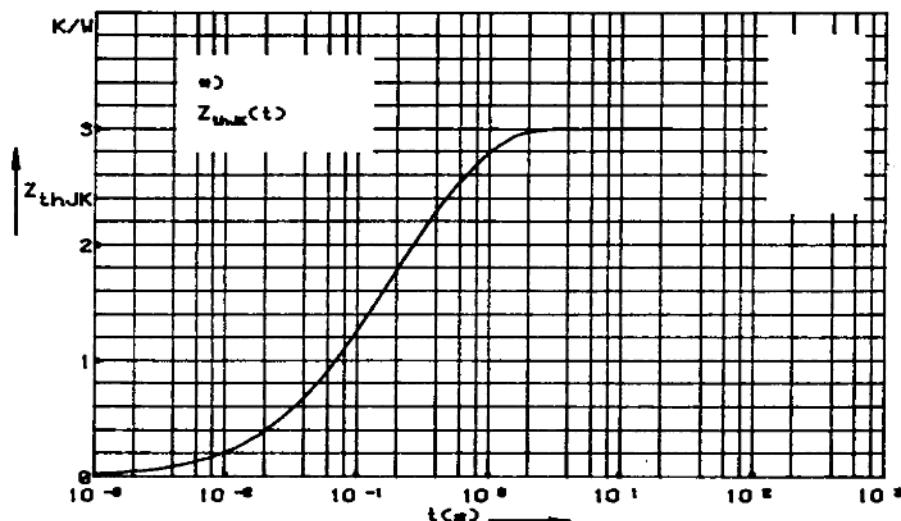


Fig. 7 Transient thermal impedance junction to heatsink per chip

Constants for Z_{thJK} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.34	0.0344
2	1.16	0.12
3	1.5	0.5